
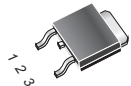


HAOPIN MICROELECTRONICS CO.,LTD.

Description

Passivated, sensitive gate triacs in a plastic envelope, intended for use in general purpose bidirectional switching and phase control applications, where high sensitivity is required in all four quadrants.

| <p>Symbol</p>  | | <p>Simplified outline</p>  <p>TO-252</p> | |
|---|----------------------|---|--|
| Pin | Description | | |
| 1 | Main terminal 1 (T1) | | |
| 2 | Main terminal 2 (T2) | | |
| 3 | gate (G) | | |
| TAB | Main terminal 2 (T2) | | |

Applications:

- ◆ Motor control
- Industrial and domestic lighting
- Heating
- Static switching

Features

- ◆ Blocking voltage to 600 V
- On-state RMS current to 4 A

| SYMBOL | PARAMETER | Value | Unit |
|--------------|--------------------------------------|-------|------|
| V_{DRM} | Repetitive peak off-state voltages | 600 | V |
| $I_{T(RMS)}$ | RMS on-state current | 4 | A |
| I_{TSM} | Non-repetitive peak on-state current | 25 | A |

| SYMBOL | PARAMETER | CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------|---|---|-----|-----|-----|------|
| R_{thj-mb} | Thermal resistance junction to mounting base | full cycle | - | - | 3.0 | K/W |
| | | half cycle | - | - | 3.7 | K/W |
| R_{thj-a} | Thermal resistance Junction to ambient | Pcb(FR4)mounteb footprint as in Fig.14 | - | 75 | - | K/W |

K/W



BT136S-600D

Sensitive Gate Triacs

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Limiting values in accordance with the Maximum system(IEC 134)

| SYMBOL | PARAMETER | CONDITIONS | MIN | MAX | UNIT | |
|--------------|---|---|-------------------|---------------------|----------------------|------------------------|
| V_{DRM} | Repetitive peak off-state Voltages | | - | 600 | V | |
| $I_{T(RMS)}$ | RMS on-state current | Full sine wave; $T_{mb} \leq 107^\circ\text{C}$ | - | 4 | A | |
| I_{TSM} | Non-repetitive peak On-state current | full sine wave; $T_j = 25^\circ\text{C}$ prior to surge | $t=20\text{ms}$ | - | 25 | A |
| | | | $t=16.7\text{ms}$ | - | 27 | A |
| I^2t | I^2t for fusing | $T=10\text{ms}$ | - | 3.1 | A^2S | |
| DI_T/dt | Repetitive rate of rise of on-state current after trigering | $I_{TM}=6\text{A}; I_G=0.2\text{A};$ $D_{IG}/dt=0.2\text{A}/\mu\text{s}$ | | - | | |
| | | | T2+G+ | - | 50 | $\text{A}/\mu\text{S}$ |
| | | | T2+G- | - | 50 | A/S |
| | | | T2-G- | - | 50 | A/S |
| | T2-G+ | - | 10 | A/S | | |
| I_{GM} | Peak gate current | | - | 2 | A | |
| V_{GM} | Peak gate voltage | | - | 5 | V | |
| P_{GM} | Peak gate power | | - | 5 | W | |
| $P_{G(AV)}$ | Average gate power | Over any 20 ms period | - | 0.5 | W | |
| T_{stg} | Storage temperature | | -40 | 150 | $^\circ\text{C}$ | |
| T_j | Operating junction Temperature | | -40 | 125 | $^\circ\text{C}$ | |

$T_j=25^\circ\text{C}$ unless otherwise stated

| SYMBOL | PARAMETER | CONDITIONS | MIN | TYP | MAX | UNIT | |
|------------------------|---------------------------|---|-------|-----|------|------|----|
| Static characteristics | | | | | | | |
| I_{GT} | Gate trigger current | $V_D=12\text{V}; I_T=0.1\text{A}$ | | - | 2.0 | 5 | mA |
| | | | T2+G+ | - | 2.5 | 5 | mA |
| | | | T2-G- | - | 2.5 | 5 | mA |
| | | | T2-G+ | - | 5.0 | 10 | mA |
| I_L | Latching current | $V_D=12\text{V}; I_{GT}=0.1\text{A}$ | T2+G+ | - | 1.6 | 10 | mA |
| | | | T2+G- | - | 4.5 | 15 | mA |
| | | | T2-G- | - | 1.2 | 10 | mA |
| | | | T2-G+ | - | 2.2 | 15 | mA |
| I_H | Holding current | $V_D=12\text{V}; I_{GT}=0.1\text{A}$ | - | 1.2 | 10 | mA | |
| V_T | On-state voltage | $I_T=5\text{A}$ | - | 1.4 | 1.70 | V | |
| V_{GT} | Gate trigger voltage | $V_D=12\text{V}; I_T=0.1\text{A}$ | - | 0.7 | 1.5 | V | |
| | | $V_D=400\text{V}; I_T=0.1\text{A}; T_j=125^\circ\text{C}$ | 0.25 | 0.4 | - | V | |
| I_D | Off-state leakage current | $V_D=V_{DRM(max)}; T_j=125^\circ\text{C}$ | - | 0.1 | 0.5 | mA | |

Dynamic Characteristics

| | | | | | | |
|-------------|--|--|---|---|---|------------------------|
| D_{VD}/dt | Critical rate of rise of Off-state voltage | $V_{DM}=67\% V_{DRM(max)}; T_j=125^\circ\text{C}; R_{GK}=1\text{K}\Omega$ Exponential waveform; Gate open circuit | - | 5 | - | $\text{V}/\mu\text{s}$ |
| t_{gt} | Gate controlled turn-on time | $I_{TM}=6\text{A}; V_D=V_{DRM(max)}; I_G=0.1\text{A};$ $DI_G/dt=5\text{A}/\mu\text{s}$ | - | 2 | - | μs |

Description

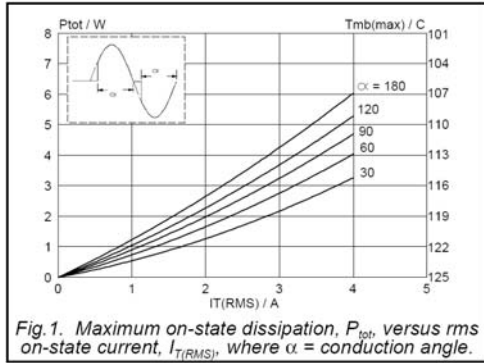


Fig. 1. Maximum on-state dissipation, P_{tot} , versus rms on-state current, $I_{T(RMS)}$, where α = conduction angle.

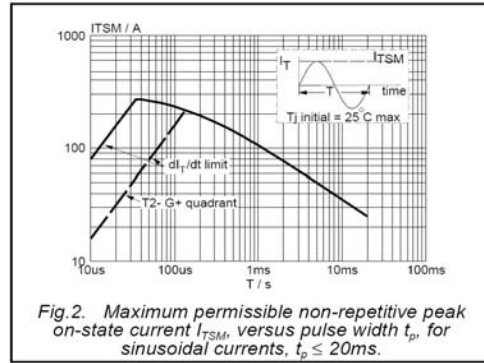


Fig. 2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \leq 20ms$.

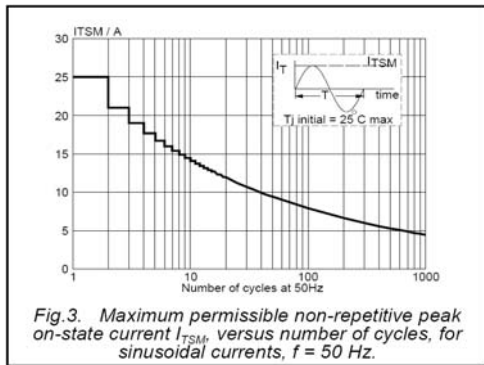


Fig. 3. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, $f = 50$ Hz.

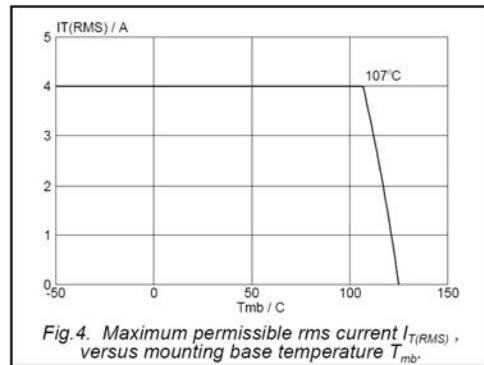


Fig. 4. Maximum permissible rms current $I_{T(RMS)}$, versus mounting base temperature T_{mb} .

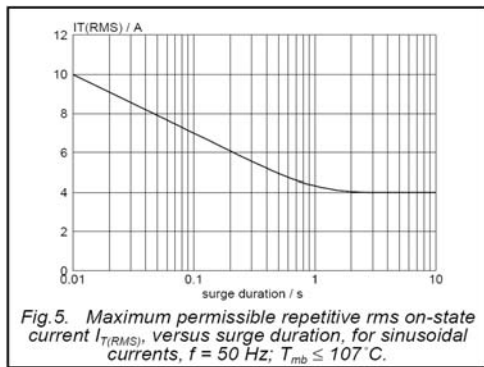


Fig. 5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, $f = 50$ Hz; $T_{mb} \leq 107$ C.

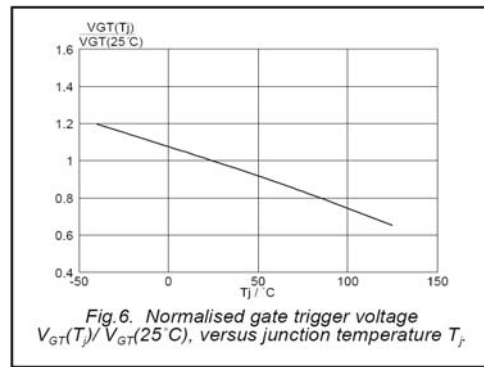
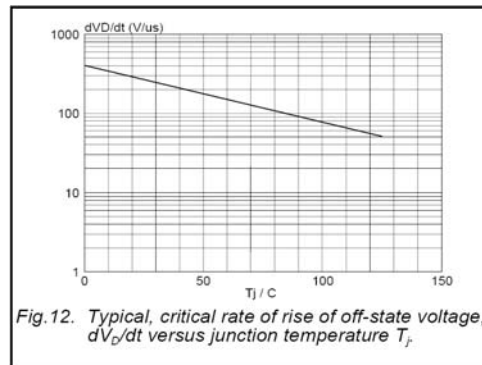
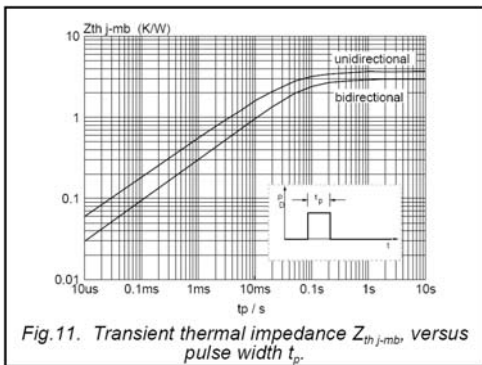
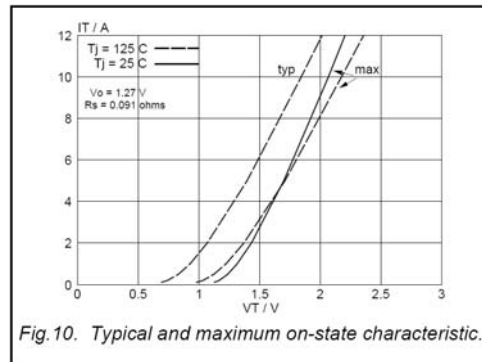
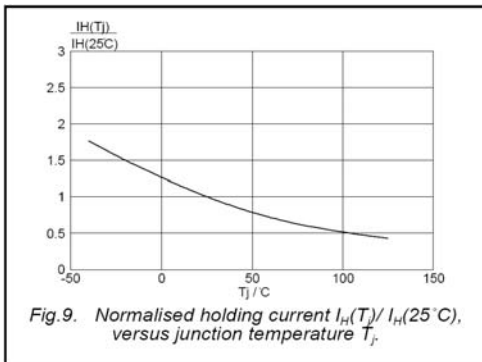
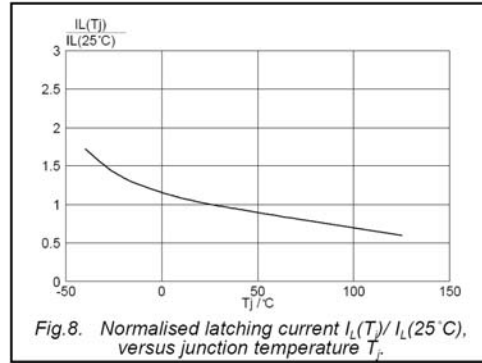
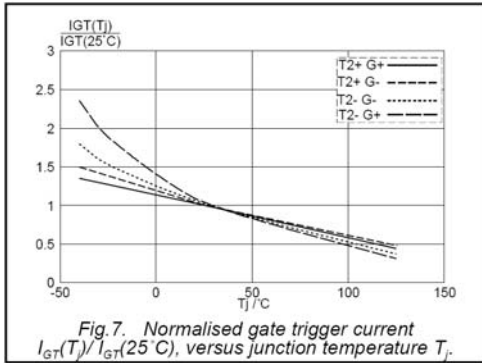


Fig. 6. Normalised gate trigger voltage $V_{GT}(T_j)/V_{GT}(25$ C), versus junction temperature T_j .

Description





BT136-600D

Sensitive Gate Triacs

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MECHANICAL DATA

Dimensions in mm
Net Mass: 0.45 g

